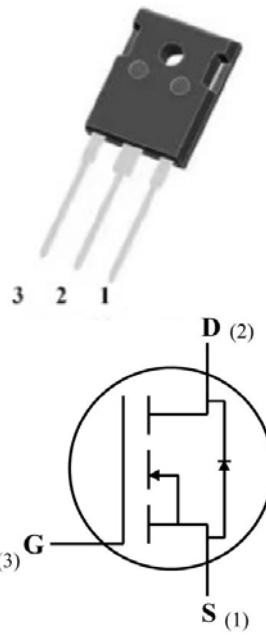


Silicon Carbide Power MOSFET (N-Channel Enhancement)

V_{DS}	650V
$I_D(25^\circ C)$	37A
$R_{DS(on)}$	60mΩ



Features

- High speed switching
- Essentially no switching losses
- Reduction of heat sink requirements
- Maximum working temperature at 175 °C
- High blocking voltage
- Fast Intrinsic diode with low recovery current
- High-frequency operation
- Halogen free, RoHS compliant
- AEC-Q101 qualified

Typical Applications

Typical applications are in power factor correction(PFC), solar inverter, uninterruptible power supply, motor drives, photovoltaic inverter, electric car and charger.

Mechanical Data

- **Package:** TO-247AB
- **Terminals:** Tin plated leads
- **Polarity:** As marked

■ Maximum Ratings ($T_c=25^\circ C$ Unless otherwise specified)

PARAMETER	SYMBOL	UNIT	VALUE	TEST CONDITIONS	NOTE
Device marking code				D206560NCTG1Q	
Drain source voltage @ $T_j=25^\circ C$	$V_{DS,max}$	V	650	$V_{GS}=0 V$, $I_D=100\mu A$	
Gate source voltage @ $T_j=25^\circ C$	$V_{GS,max}$	V	-8/+19	Absolute maximum values	
Gate source voltage @ $T_j=25^\circ C$	$V_{GS,op}$	V	-4/+15	Recommended operational values	Note1、2
Continuous drain current @ $T_c=25^\circ C$	I_D	A	37	$V_{GS}=15V$, $T_c=25^\circ C$	Fig.18
Continuous drain current @ $T_c=100^\circ C$			28	$V_{GS}=15V$, $T_c=100^\circ C$	
Pulsed drain current	$I_{D(pulsed)}$	A	99	Pulse width t_p limited by $T_{j,max}$	Fig.23
Power Dissipation	P_{TOT}	W	153	$T_c=25^\circ C$, $T_j = 175^\circ C$	Fig.17
Power Dissipation			66	$T_c=110^\circ C$, $T_j = 175^\circ C$	
Operating junction and Storage temperature range	T_j, T_{stg}	°C	-55 to +175		
Soldering temperature	T_L	°C	260	1.6mm (0.063") from case for 10s	
Mounting torque	T_M	Nm	0.6	M3 screw Maximum of mounting process: 3	



YJD206560NCTG1Q

■ Static Electrical Characteristics (Tc=25°C unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Gate threshold voltage	V _{GS(th)}	V	2.0	2.4	3.1	V _{DS} =V _{GS} , I _D =5mA	Fig.4, 11
				2.0		V _{DS} =V _{GS} , I _D =5mA, Tj=175°C	
Drain source breakdown voltage	V _{(BR)DSS}	V	650			V _{GS} =0, I _D =100uA	
Zero gate voltage drain current	I _{DSS}	uA		1	20	V _{DS} =650V, V _{GS} =0V	Fig.16
Gate source leakage current	I _{GSS}	nA			250	V _{GS} =15V, V _{DS} =0V	
Current drain source on-state resistance	R _{DS ON}	mΩ		60	79	V _{GS} =15V, I _D =13.2A	Fig.5, 6, 7
				90		V _{GS} =15V, I _D =13.2A, Tj=175°C	
Internal gate resistance	R _g	Ω		3		f=1MHz	
Diode forward voltage	V _{SD}	V		5.0		V _{GS} =-4V, I _{SD} =6.6A	Fig.8
				2.8		V _{GS} =0V, I _{SD} =6.6A Tj=175°C	Fig.9
Transconductance	g _f	S		10		V _{DS} =20V, I _D =13.2A	Fig.4
				9		V _{DS} =20V, I _D =13.2A, Tj=175°C	

■ Dynamic Electrical Characteristics (Tc=25°C unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Input capacitance	C _{iss}	pF		1125		V _{DS} =400V, V _{GS} =0V, Tj=25°C, f=100kHz, V _{AC} =25mV	Fig.13, 14
Output capacitance	C _{oss}			71			
Reverse capacitance	C _{rss}			7			
C _{oss} stored energy	E _{oss}	uJ		7		V _{DS} =400V, V _{GS} =-4/15V, I _D =13.2A	Fig.15
Gate source charge	Q _{gs}	nC		13			Fig.12
Gate drain charge	Q _{gd}			17			
Gate charge	Q _g			46			

■ Switching Characteristics (Tc=25°C unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Turn on switching energy	E _{on}	uJ		67		V _{DD} =400V, V _{GS} =-4/+15V, I _D =13.2A, R _g =2.5Ω, L=135uH	Fig.21, 22
Turn off switching energy	E _{off}			6			
Turn on delay time	t _{d(on)}	ns		8		V _{DD} =400V, V _{GS} =-4/+15V, I _D =13.2A, R _g =2.5Ω, L=135uH	Fig.21, 22
Rise time	t _r			11			
Turn off delay time	t _{d(off)}	ns		17		V _{DD} =400V, V _{GS} =-4/+15V, I _D =13.2A, R _g =2.5Ω, L=135uH	Fig.21, 22
Fall time	t _f			5			



■ **Body diode characteristics** (T_c=25°C unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Diode forward voltage	V _{SD}	V		5.0		V _{GS} =-4V, I _{SD} =6.6A	Fig.8
				2.8		V _{GS} =0V, I _{SD} =6.6A T _j =175°C	Fig.9
Continuous diode forward current	I _S	A		24		V _{GS} =-4V, T _c =25°C	Note1
Reverse recovery time	trr	nS		16		V _R =400V, V _{GS} =-4V, I _D =13.2A, dI/dt=2400A/uS	
Reverse recovery charge	Qrr	nC		110			
Peak reverse recovery current	Irrm	A		12			

Note 1: When using SiC Body Diode the maximum recommended V_{GS} = -4V

Note 2: MOSFET can also safely operate at 0/15 V

■ **Thermal Characteristics** (T_a=25°C Unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Typ.
Thermal resistance	R _{θJ-C}	°C/W	0.98

■ **Typical Characteristics**

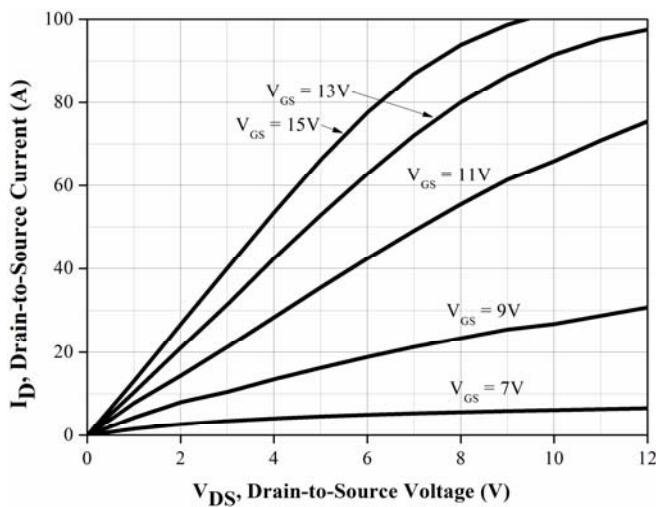


Figure 1. Output Characteristics T_j = -55°C

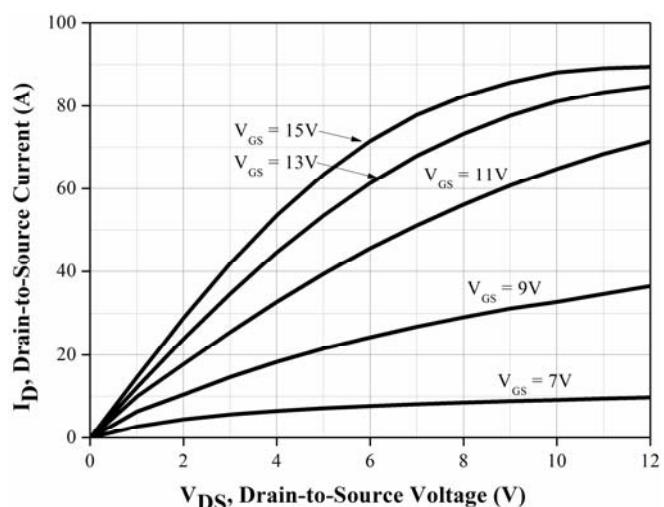


Figure2. Output Characteristics T_j = 25°C

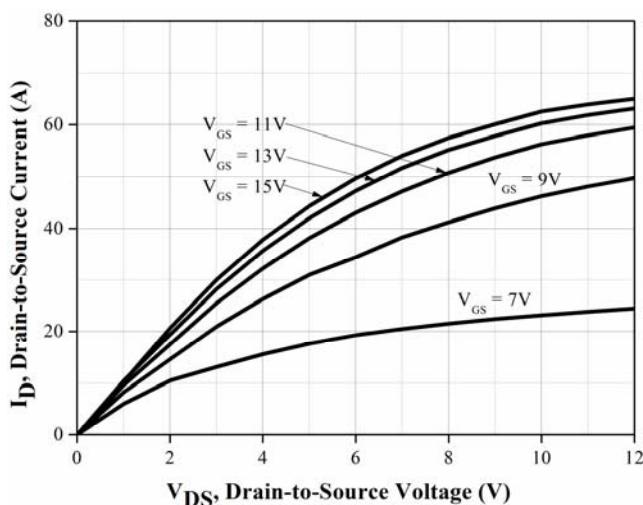


Figure 3. Output Characteristics $T_j = 175^\circ\text{C}$

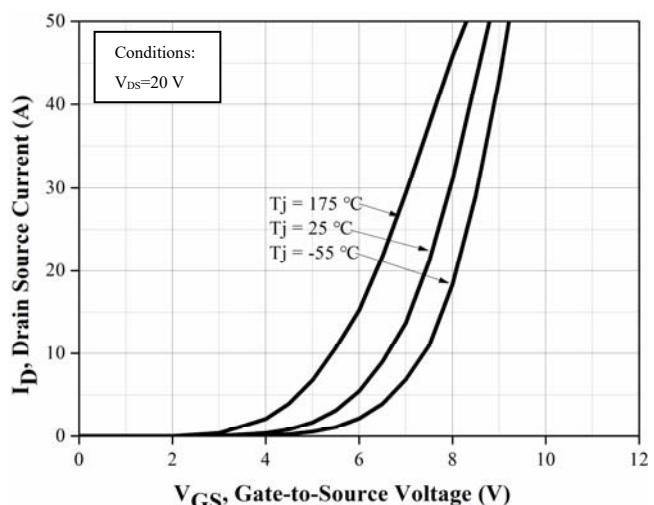


Figure 4. Transfer Characteristics for various junction temperature

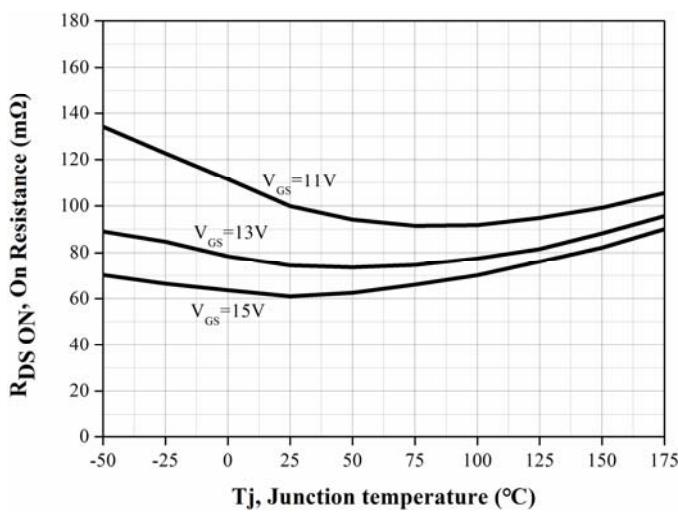


Figure 5. On-resistance vs. temperature for various gate voltage

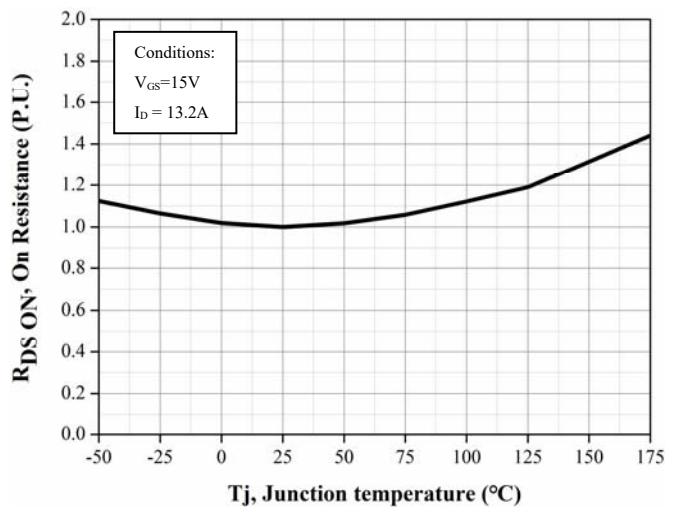


Figure 6. Normalized on-resistance vs. temperature

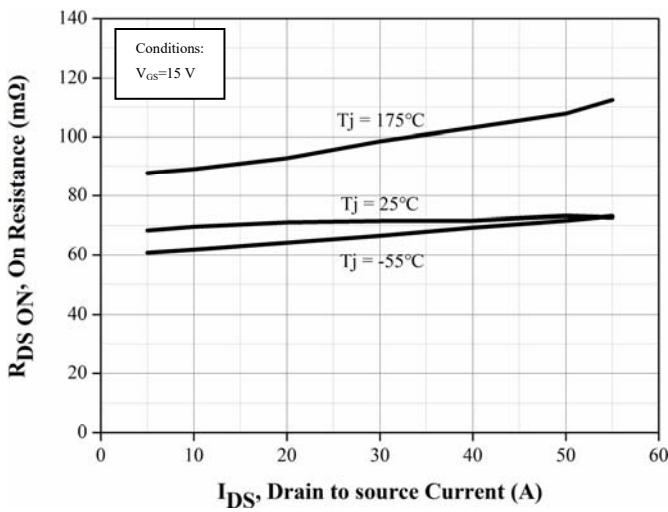


Figure 7. On-resistance vs. drain current

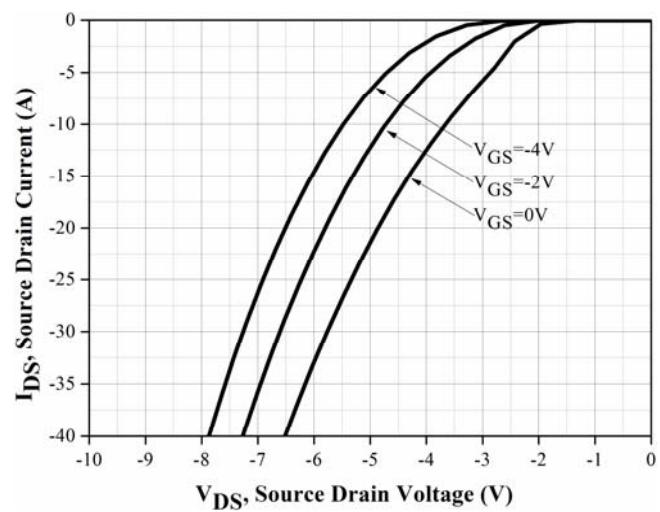


Figure 8. Body diode characteristic at $T_j = 25^\circ\text{C}$

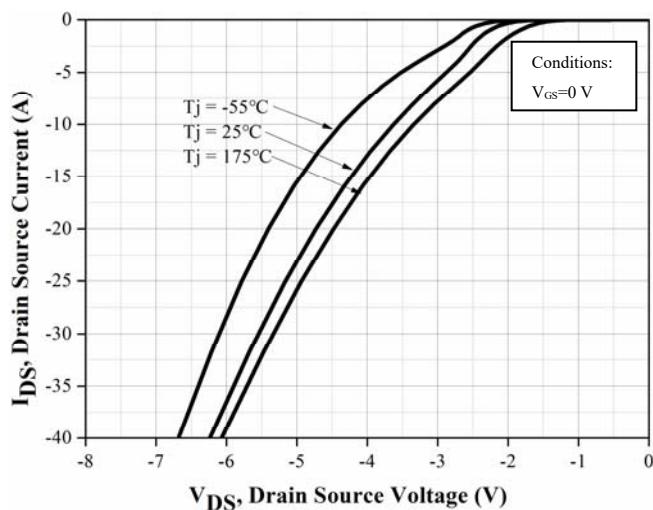


Figure 9. Body diode characteristic

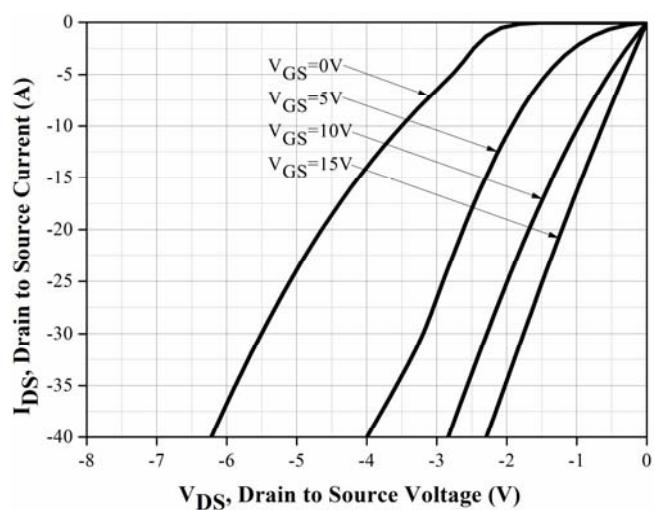


Figure 10. 3rd quadrant characteristic at $T_j = 25^\circ\text{C}$

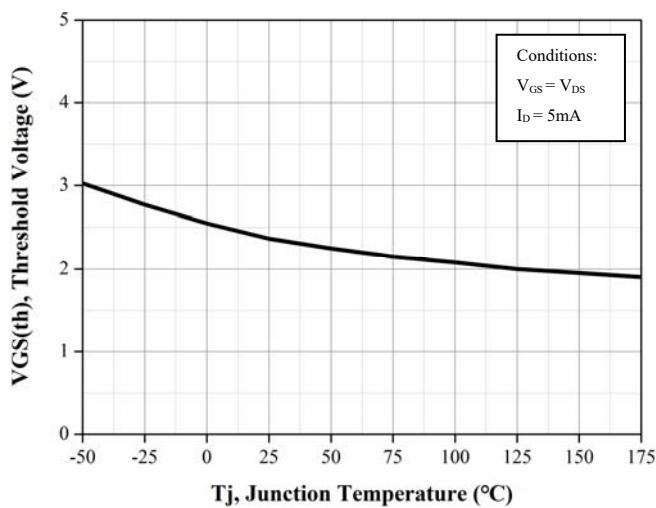


Figure 11. Threshold voltage vs. temperature

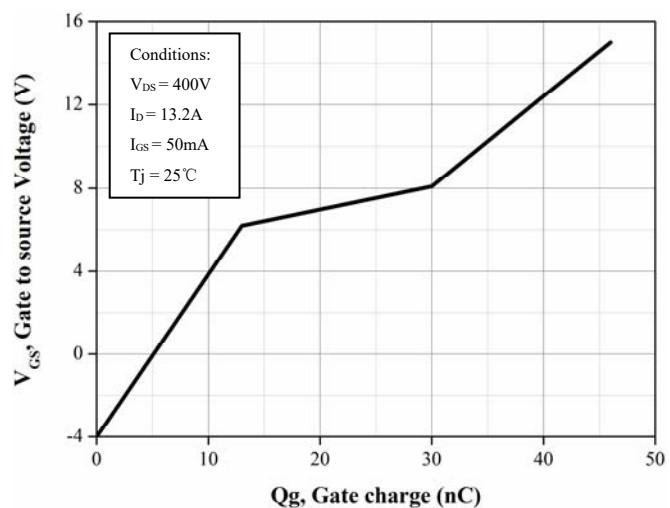


Figure 12. Gate charge characteristic

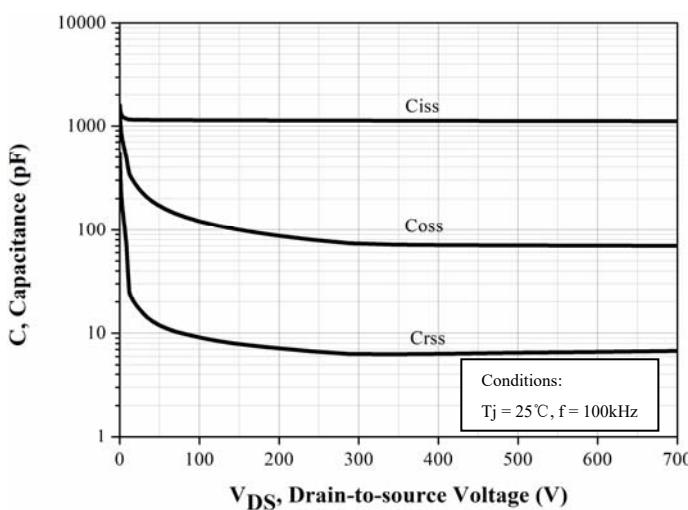


Figure 13. Capacitances vs. drain source voltage (0-700V)

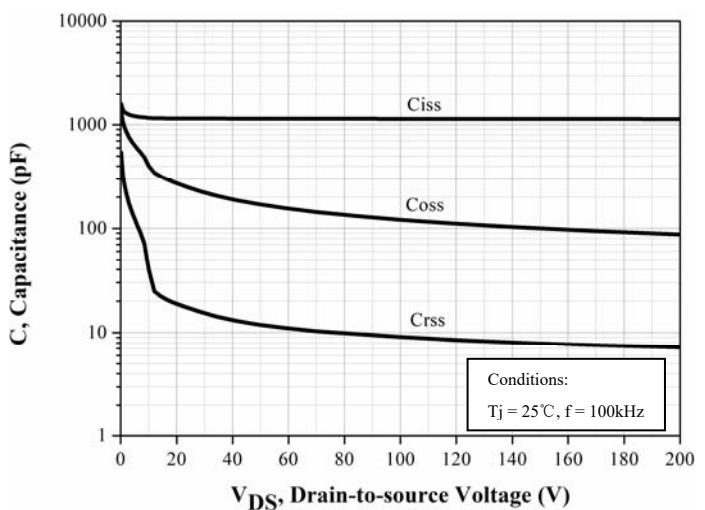


Figure 14. Capacitances vs. drain source voltage (0-200V)

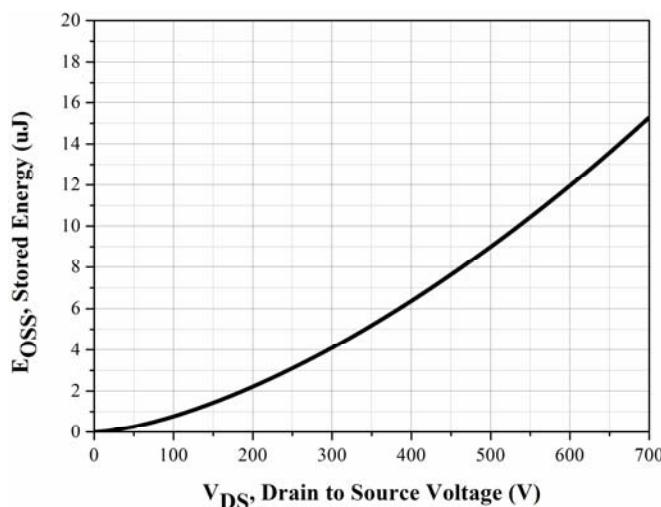


Figure 15. Output capacitor stored energy

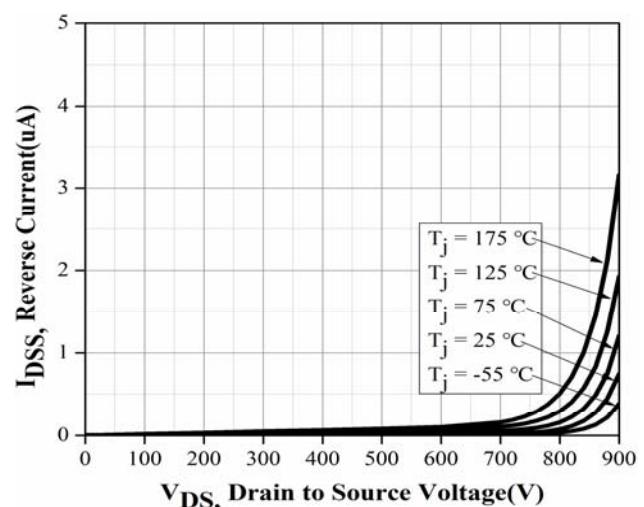


Figure 16. Reverse characteristics vs. T_j

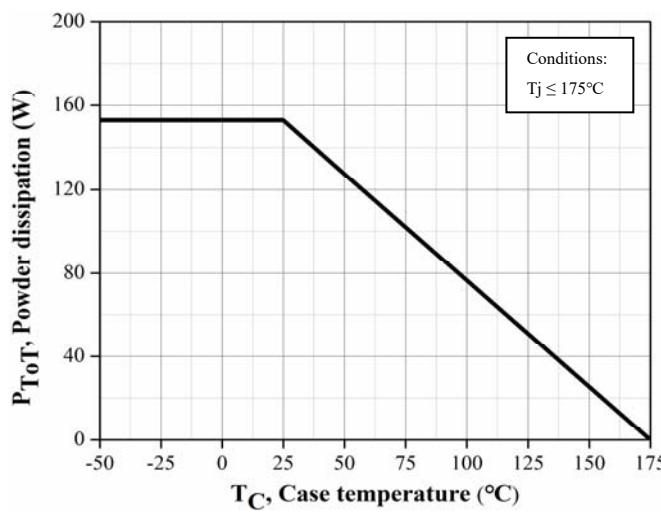


Figure 17. Maximum power dissipation derating vs. case temperature

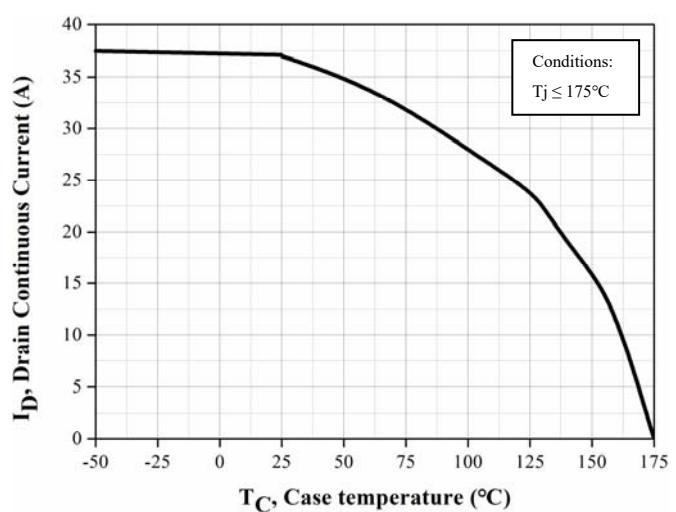


Figure 18. Continuous drain current derating vs. case temperature

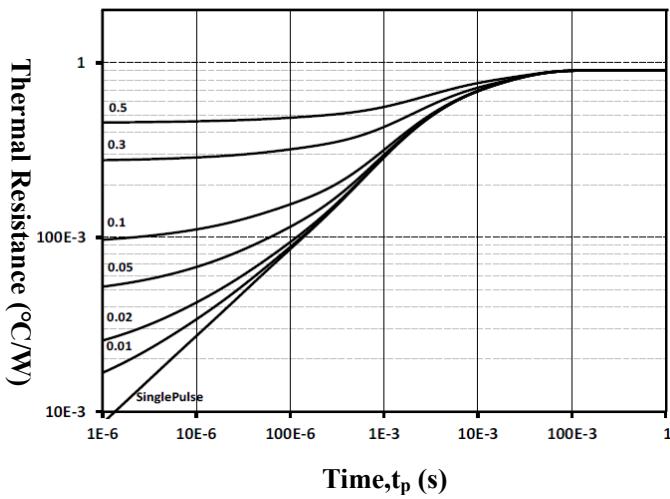


Figure 19. Transient thermal impedance (junction - case)

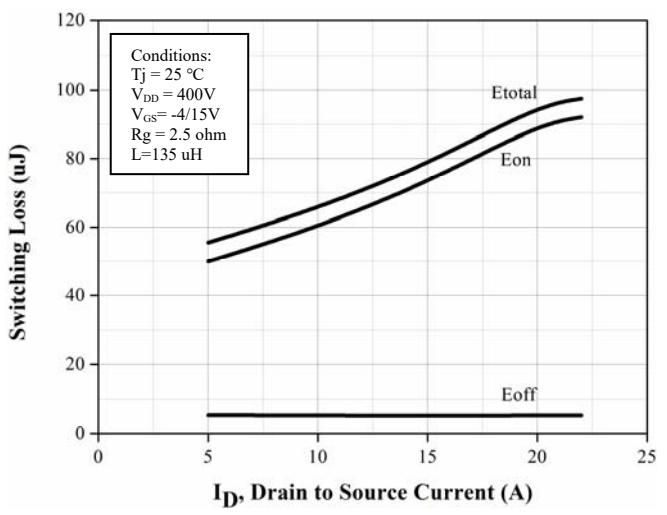


Figure 20. Clamped Inductive switching energy vs. drain current

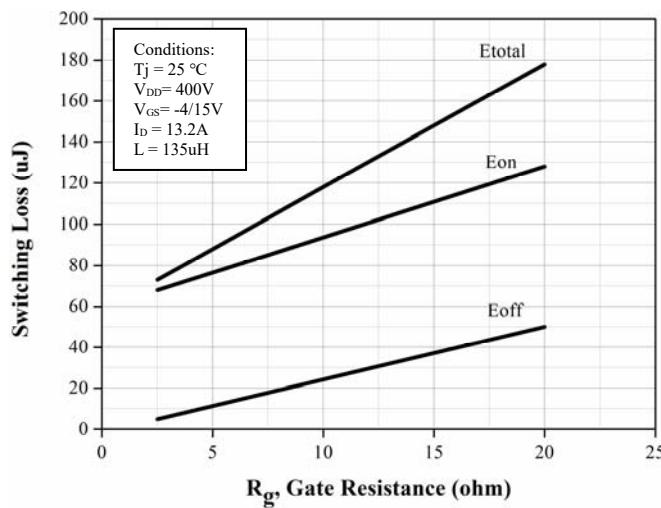


Figure 21. Clamped inductive switching energy vs. R_g

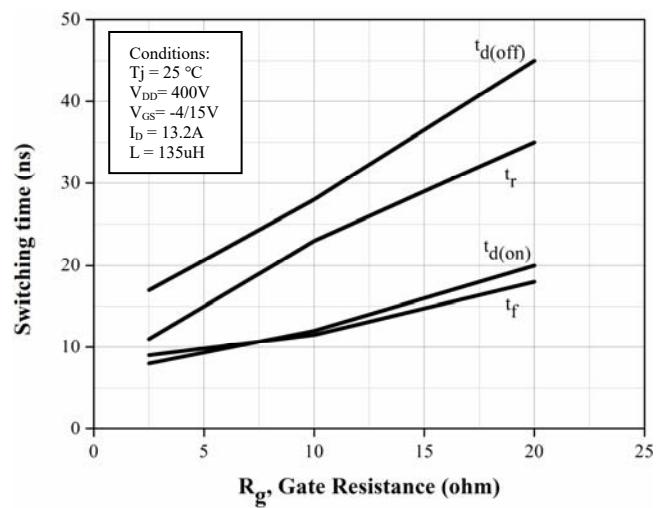


Figure 22. Switching times vs. R_g

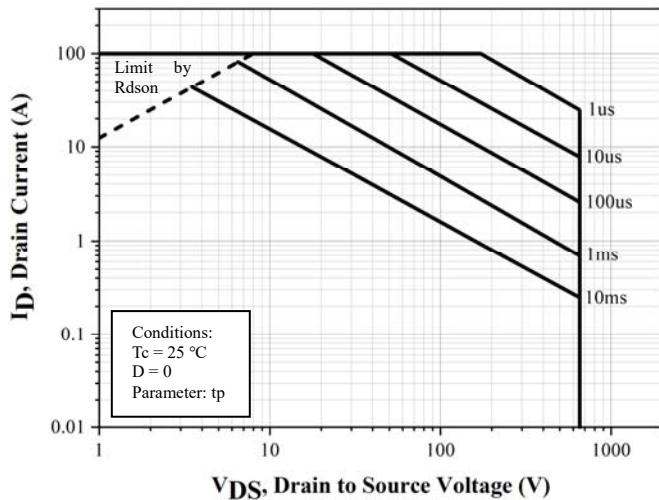


Figure 23. Safe Operating Area

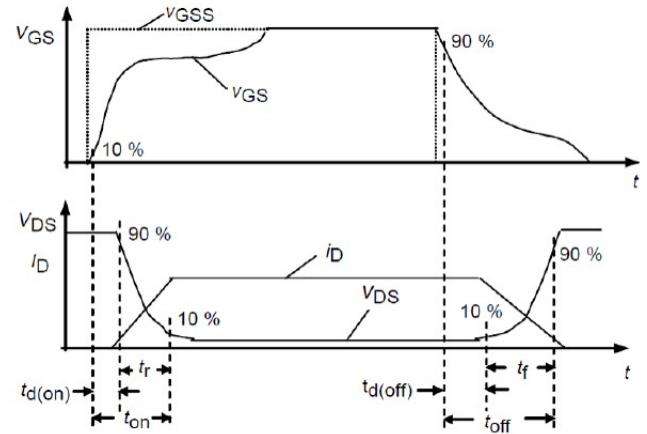


Figure 24. Switching Times Definition

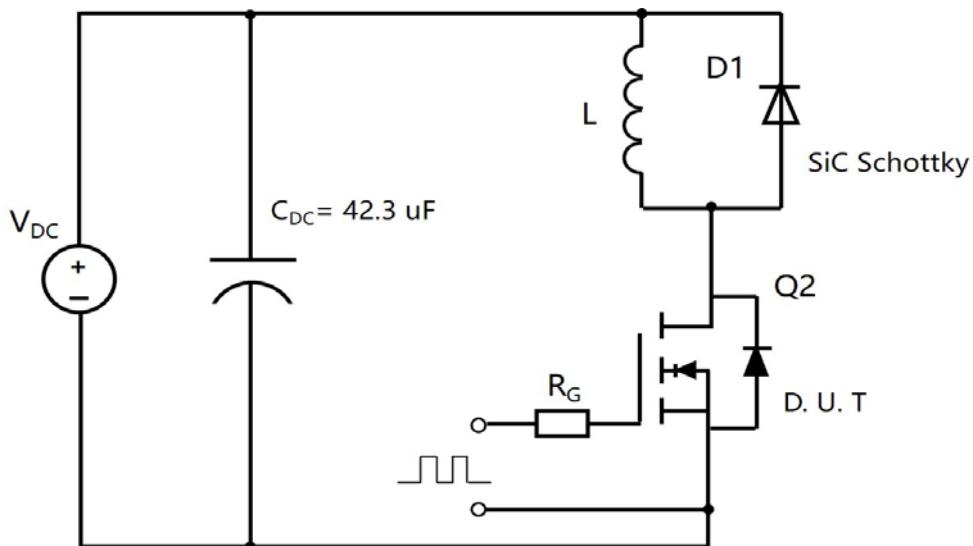
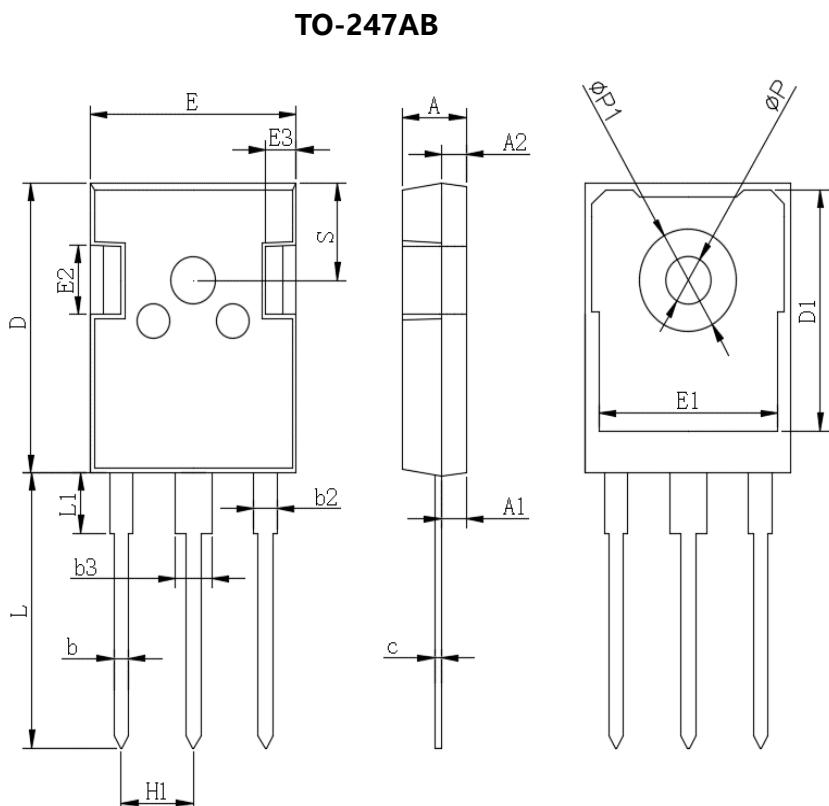


Figure 25. Clamped Inductive Switching Waveform Test Circuit

**■Outline Dimensions**

TO-247AB		
Dim	Min	Max
A	4.80	5.20
A1	2.21	2.61
A2	1.85	2.15
b	1.0	1.4
b2	1.91	2.21
C	0.5	0.7
D	20.70	21.30
D1	16.25	16.85
E	15.50	16.10
E1	13.0	13.6
E2	4.80	5.20
E3	2.30	2.70
L	19.62	20.22
L1	-	4.30
ØP	3.40	3.80
ØP1	-	7.30
S	6.15TYP	
H1	5.44TYP	
b3	2.80	3.20



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